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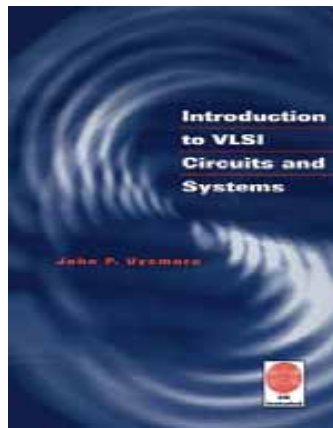
National Chin-Yi University of Technology

# Introduction to VLSI Circuits and Systems

## 積體電路概論

### Chapter 07

### Electronic Analysis of CMOS Logic Gates



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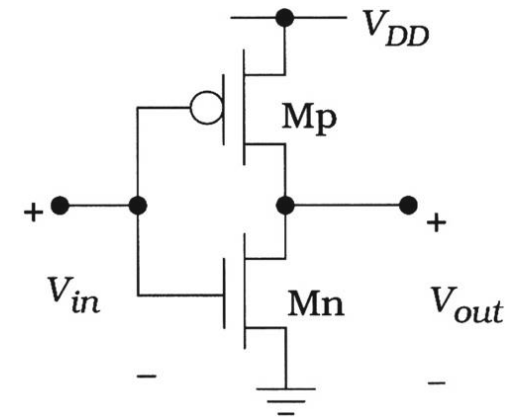
# Outline

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- ❑ DC Characteristic of the CMOS Inverter
- ❑ Inverter Switching Characteristic
- ❑ Power Dissipation
- ❑ DC Characteristic: NAND and NOR Gates
- ❑ NAND and NOR Transient Response
- ❑ Analysis of Complex Logic Gates
- ❑ Gate Design for Transient Performance
- ❑ Transmission Gates and Pass Transistors

# The Inverter Circuit

- ❑ The CMOS inverter gives the basic for calculating the electrical characteristic of logic gates
  - » The conduction states of  $M_n$  and  $M_p$  is determined by input voltage  $V_{in}$
  - » Two types of calculations: *DC analysis* and *transient analysis*
- ❑ DC analysis
  - » Provide a direct mapping of the input to the output, such that to determine  $V_{out}$
- ❑ Transient analysis
  - » The input voltage is an explicit function of time  $V_{in}(t)$  corresponding to a changing logic value



$$\text{pFET: } V_{Tp} < 0$$
$$\beta_p = k'_p \left( \frac{W}{L} \right)_p$$

$$\text{nFET: } V_{Tn} > 0$$
$$\beta_n = k'_n \left( \frac{W}{L} \right)_n$$

Figure 7.1 The CMOS inverter circuit

# DC Analysis of Inverter

- The DC characteristics of the inverter are portrayed in the *voltage transfer characteristic* (VTC), which is a plot of  $V_{out}$  as a function of  $V_{in}$

- » Simply, the output high voltage of the circuits as

$$V_{OH} = V_{DD} \quad (7.1) \quad (V_{in} = 0)$$

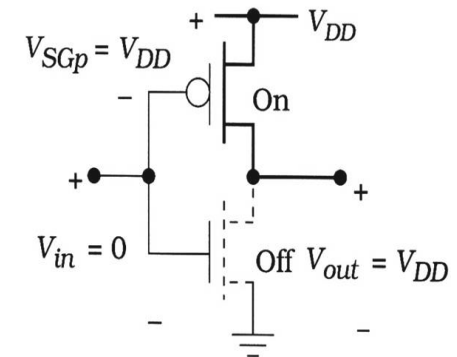
- » The output low voltage

$$V_{OL} = 0 \text{ V} \quad (7.2) \quad (V_{in} = V_{DD})$$

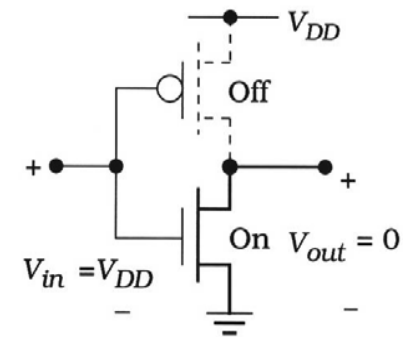
- » The logic swing at the output is

$$V_L = V_{OH} - V_{OL} = V_{DD} \quad (7.3) \quad (\text{full-rail output})$$

- Since this is equal to the full value of the power supply, this is called a *full-rail output*



(a) Low input voltage



(b) High input voltage

Figure 7.2  $V_{OH}$  and  $V_{OL}$  for the inverter

# VTC of the Inverter

- Starting with an input voltage of  $V_{in} = 0V$  and then increasing it up to a value of  $V_{in} = V_{DD}$

$$\begin{aligned} V_{GSn} &= V_{in} \\ V_{SGp} &= V_{DD} - V_{in} \end{aligned} \quad (7.4)$$

- »  $M_p$  goes into cutoff when

$$V_{in} = V_{DD} - |V_{Tp}| \quad (7.5)$$

- » The logic 0 and 1 voltage ranges are defined by the changing slope of the VTC

- A logic 0 input voltage (input low voltage)

$$0 \leq V_{in} \leq V_{IL} \quad (7.6)$$

- A logic 1 input voltage (input high voltage)

$$V_{IH} \leq V_{in} \leq V_{DD} \quad (7.7)$$

- » The *voltage noise margins* give a quantitative measure of how stable the inputs are with respect to coupled electromagnetic signal interface, there are

$$VNM_H = V_{OH} - V_{IH} \quad (7.8)$$

$$VNM_L = V_{IL} - V_{OL}$$

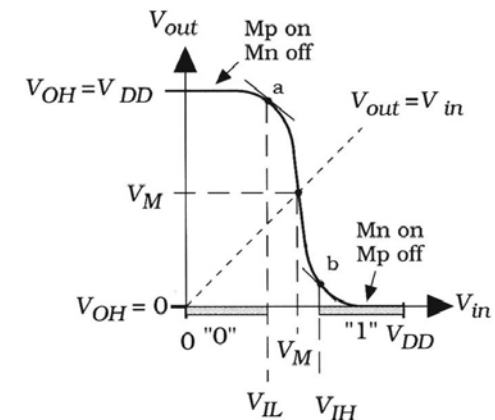
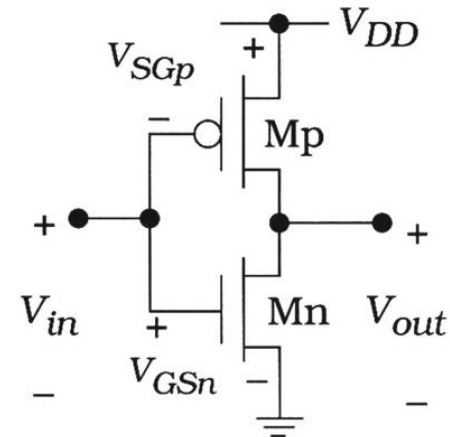
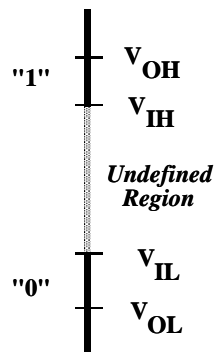
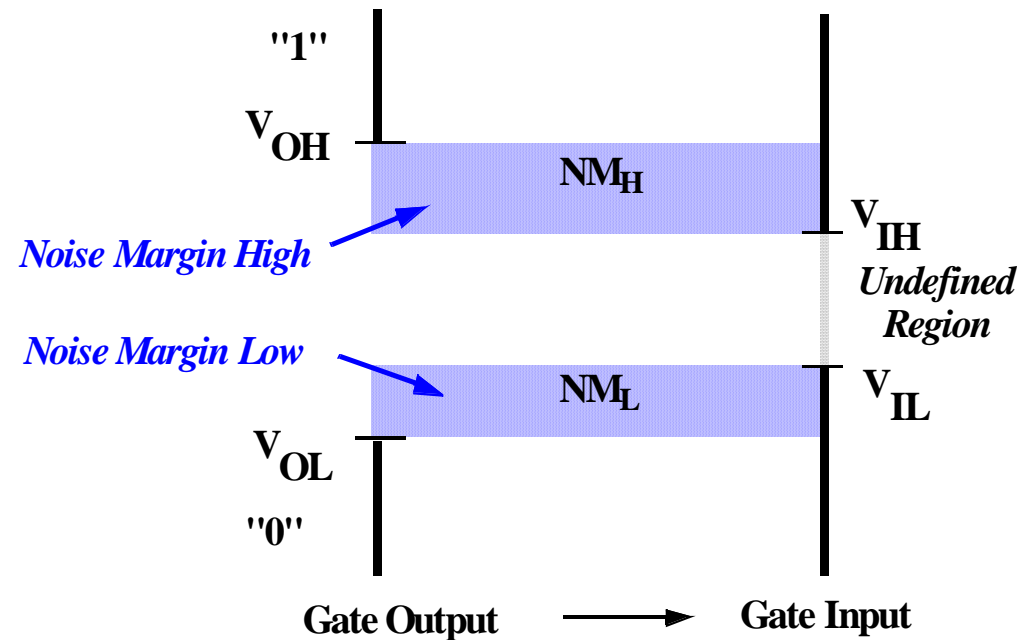
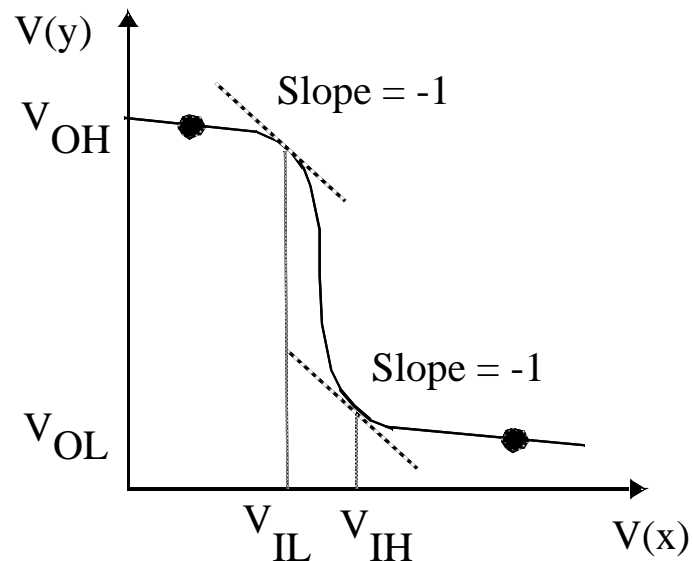


Figure 7.3 Voltage transfer curve for the NOT gate

# Definition of Noise Margins



$$VNM_H = V_{OH} - V_{IH} \quad (7.8)$$

$$VNM_L = V_{IL} - V_{OL}$$

# Midpoint Voltage $V_M$

$$I_{Dn} = I_{Dp} \quad (\text{Let } V_{in} = V_{out} = V_M) \quad (7.9)$$

$$\frac{\beta_n}{\beta_p} = \frac{\kappa'_n \left( \frac{W}{L} \right)_n}{\kappa'_p \left( \frac{W}{L} \right)_p} \quad (7.15)$$

$$V_{sat} = V_{GSn} - V_{Tn} = V_M - V_{Tn} \quad (7.10)$$

$$\frac{\kappa'_n}{\kappa'_p} \approx 2 \text{ to } 3 \quad (7.16)$$

$$V_{DSn} > V_{sat} = V_M - V_{Tn} \quad (7.11)$$

$$\frac{\kappa'_n}{\kappa'_p} = \frac{\mu_n}{\mu_p} = \gamma \quad (7.17)$$

$$\frac{\beta_n}{2} (V_M - V_{Tn})^2 = \frac{\beta_p}{2} (V_{DD} - V_M - |V_{Tp}|)^2 \quad (7.12)$$

Symmetrical inverter principle

$$\sqrt{\frac{\beta_n}{\beta_p}} (V_M - V_{Tn}) = V_{DD} - V_M - |V_{Tp}| \quad (7.13)$$

$$V_M = \frac{V_{DD} - |V_{Tp}| + \sqrt{\frac{\beta_n}{\beta_p}} V_{Tn}}{1 + \sqrt{\frac{\beta_n}{\beta_p}}} \quad (7.14)$$

$$V_M = \frac{1}{2} V_{DD} \quad (7.18)$$

$$\frac{\beta_n}{\beta_p} = \left( \frac{\frac{1}{2} V_{DD} - |V_{Tp}|}{\frac{1}{2} V_{DD} - V_{Tn}} \right)^2 \quad (7.19)$$

$$\beta_n = \beta_p \quad (7.20)$$

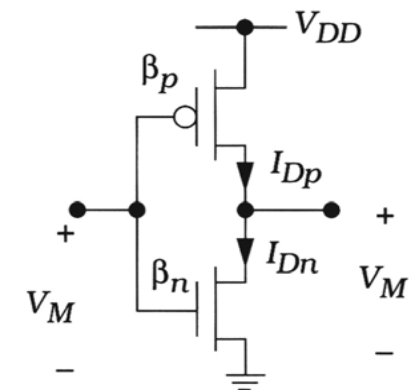
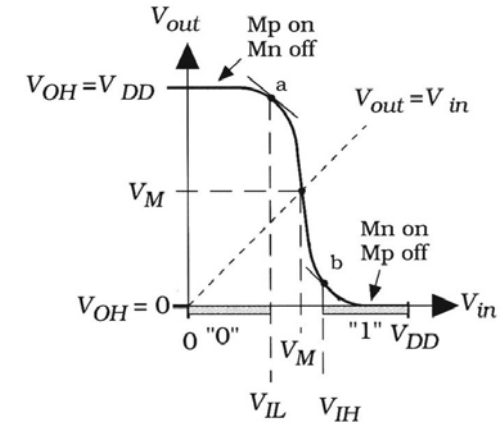
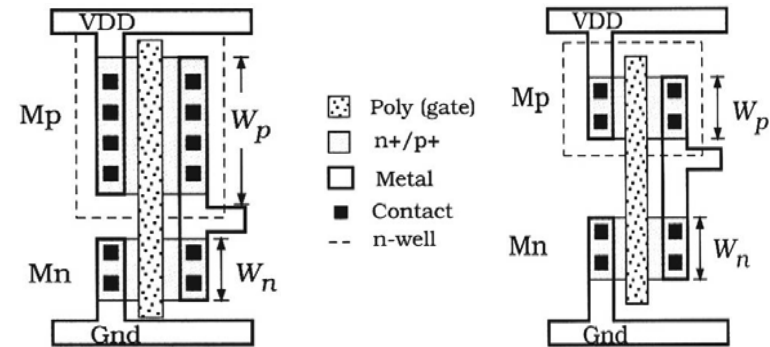


Figure 7.4 Inverter voltage for  $V_M$  calculation

# VTC Variation

- ❑ In Figure 7.5(a), the pFET has a width of about  $W_p = 2W_n$ 
  - »  $V_M = (V_{DD}/2)$
- ❑ In Figure 7.5(b), the pFET has a width of about  $W_p = W_n$ 
  - »  $V_M < (V_{DD}/2)$
- ❑ At the physical level, the relative device sizes contained in the ratio ( $\beta_n / \beta_p$ ) determine the switching points



(a) Large pFET design

(b) Equal aspect ratios

Figure 7.5 Comparison of the layouts

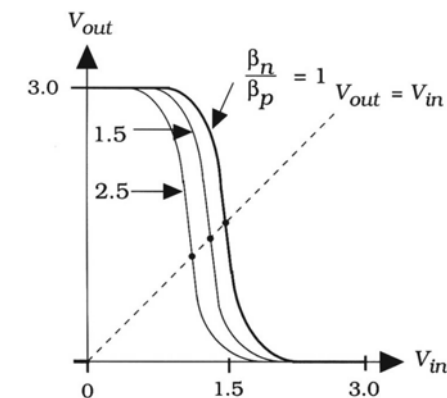


Figure 7.6 Dependence of  $V_M$  on the device ratio



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# Switching Characteristic

- ❑ High-speed digital system design requires that logic gates introduce a minimum amount of time delay when the inputs change
  - » The output 1-to-0 transition introduces a *fall time* delay of  $t_f$
  - » The output 0-to-1 transition introduces a *rise time* delay of  $t_r$
- ❑ The rise time and fall time can be calculated by analyzing the electronic transitions of the circuits
  - » parasitic resistance
  - » parasitic capacitances of the transistors

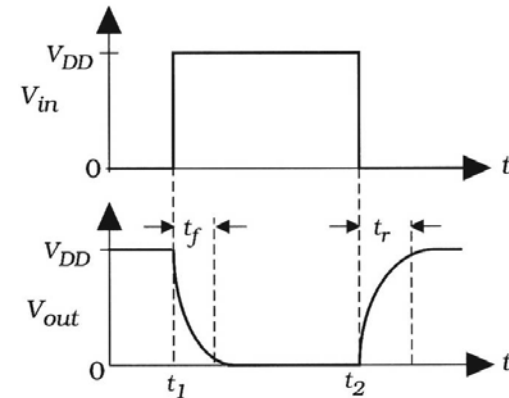
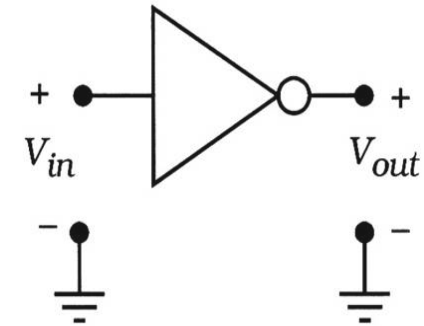


Figure 7.7 General switching waveforms

# RC Model of Inverter

- Both FETs can be replaced by their switch equivalents, which results in the simplified RC model
  - » Given the aspect ratios  $\left(\frac{W}{L}\right)_n$  and  $\left(\frac{W}{L}\right)_p$

$$R_n = \frac{1}{\beta_n (V_{DD} - V_{Tn})} \quad (7.28)$$

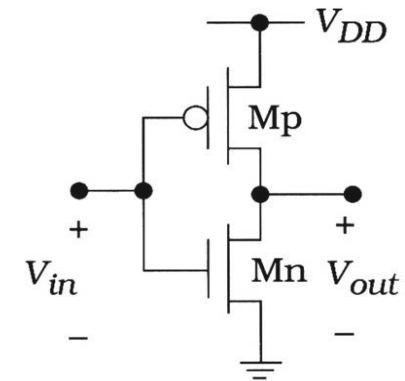
$$R_p = \frac{1}{\beta_p (V_{DD} - |V_{Tp}|)}$$

- » Finding the capacitance  $C_{Dn}$  and  $C_{Dp}$  at the output node

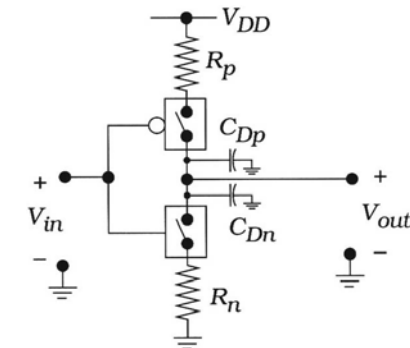
$$C_{Dn} = C_{GSn} + C_{DBn} = \frac{1}{2} C_{ox} L' W_n + C_{jn} A_n + C_{jsw n} P_n \quad (7.29)$$

$$C_{Dp} = C_{GSp} + C_{DBp} = \frac{1}{2} C_{ox} L' W_p + C_{jp} A_{pp} + C_{jsw p} P_p$$

- It is significant that increasing the channel width of a FET increases the parasitic capacitance values



(a) FET circuit



(b) RC switch model equivalent

Figure 7.8 RC switch model equivalent for the CMOS inverter

# Fan-out (FO)

- The fan-out gates act as a *load* to the driving circuit because of their *input capacitance*  $C_{in}$

» Therefore, the total input capacitance is (Figure 7.9(a))

$$C_{in} = C_{Gp} + C_{Gn} \quad (7.30)$$

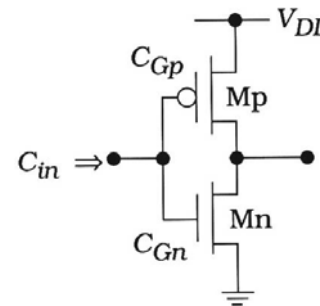
» In Figure 7.9(b), the external load capacitance  $C_L$  is

$$C_L = 3C_{in} \quad (7.31)$$

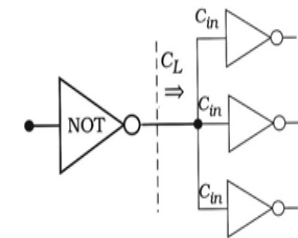
- In Figure 7.10 where the total output capacitance is defined as

$$C_{out} = C_{FET} + C_L \quad (7.32)$$

$$C_{FET} = C_{Dn} + C_{Dp} \quad (7.33)$$

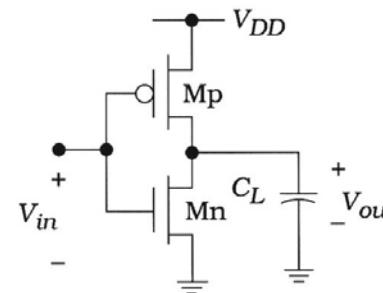


(a) Single stage

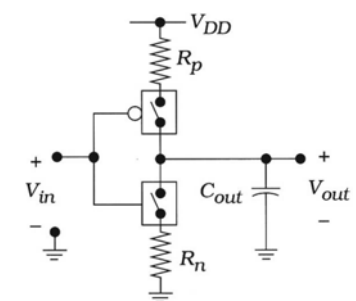


(b) Loading due to fan-out

Figure 7.9 Input capacitance and load effects



(a) External load



(b) Complete switch model

Figure 7.10 Evolution of the inverter switching model

# Fall Time Calculation

- Initially,  $V_{out}(0) = V_{DD}$ , and  $V_{in} = 0$  V and is switched to  $V_{in} = V_{DD}$  at time  $t = 0$ ; we time shift this event to occur at  $t = 0$

» The current leaving the capacitor is

$$i = -C_{out} \frac{dV_{out}}{dt} = \frac{V_{out}}{R_n} \quad (7.42)$$

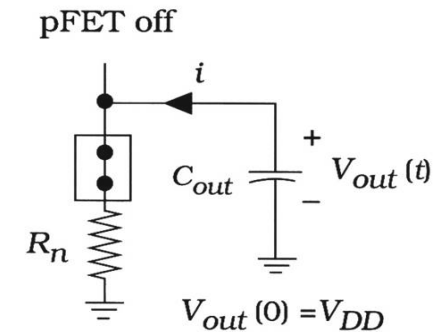
» The differential equation for the discharge events

$$V_{out}(t) = V_{DD} e^{-\frac{t}{\tau_n}}, \text{ where } \tau_n = R_n C_{out} \quad (7.43, 44)$$

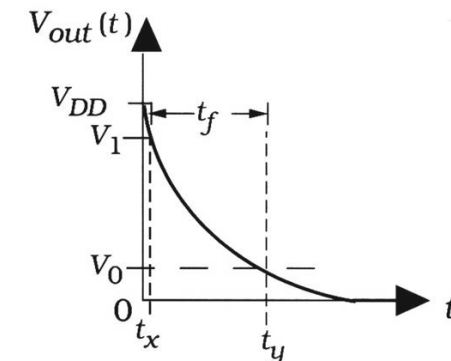
$$\Rightarrow t = \tau_n \ln \left( \frac{V_{DD}}{V_{out}} \right) \quad (7.45)$$

$$\begin{aligned} t_f &= t_y - t_x \\ &= \tau_n \ln \left( \frac{V_{DD}}{0.1V_{DD}} \right) - \tau_n \ln \left( \frac{V_{DD}}{0.9V_{DD}} \right) \\ &= \tau_n \ln(9) \end{aligned} \quad (7.46)$$

$$\Rightarrow t_f \approx 2.2\tau_n \quad (t_{HL} = t_f) \quad (7.48, 49)$$



(a) Discharge circuit



(b) Output waveform

Figure 7.12 Discharge circuit for the fall time calculation

# The Rise Time

- Initially,  $V_{out}(0) = 0$  V, and  $V_{in} = V_{DD}$  and is switched to  $V_{in} = 0$  V at  $t = 0$ ; we time shift this event to occur at  $t = 0$

» The charge current is given by

$$i = C_{out} \frac{dV_{out}}{dt} = \frac{V_{DD} - V_{out}}{R_p} \quad (7.50)$$

» The differential equation for the charge events

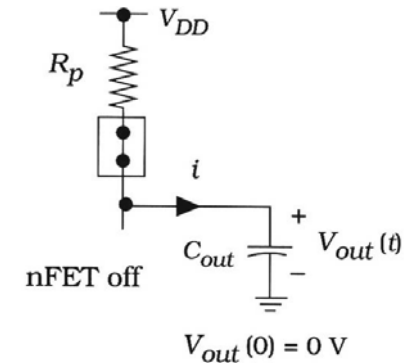
$$V_{out}(t) = V_{DD} \left[ 1 - e^{-\frac{t}{\tau_p}} \right], \text{ where } \tau_p = R_p C_{out} \quad (7.51, 52)$$

$$t_r = t_v - t_u \quad (7.53)$$

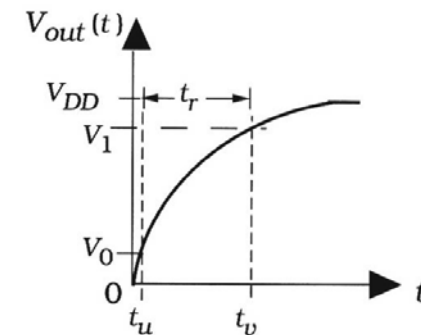
$$\Rightarrow t_r = \ln(9) \tau_p \approx 2.2 \tau_p \quad (7.54)$$

$$\Rightarrow f_{max} = \frac{1}{t_{HL} + t_{LH}} = \frac{1}{t_r + t_f} \quad (7.55)$$

- $f_{max}$  is the largest frequency that can be applied to the gate and still allow the output to settle to a definable state



(a) Charge circuit



(b) Output waveform

Figure 7.13 Rise time calculation

# Propagation Delay (1/2)

- The propagation delay time  $t_p$  is often used to estimate the “reaction” delay time from input to output

$$t_p = \frac{(t_{pf} + t_{pr})}{2} \quad (7.64)$$

- »  $t_{pf}$  is the output fall time from the maximum level to the “50%” voltage line, i.e., from  $V_{DD}$  to  $(V_{DD}/2)$

$$t_{pf} = \ln(2)\tau_n \quad (7.65)$$

- »  $t_{pr}$  is the propagation rise time from 0 V to  $(V_{DD}/2)$

$$t_{pr} = \ln(2)\tau_p \quad (7.65)$$

$$\Rightarrow t_p \approx 0.35(\tau_n + \tau_p) \quad (7.66)$$

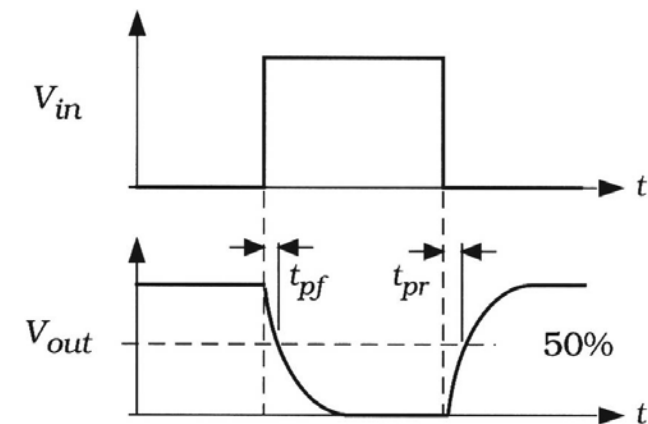


Figure 7.14 Propagation time definitions

- Commonly used in basic logic simulation programs because does not provide detailed information on the rise and fall times as individual quantities

# Propagation Delay (2/2)

- The rise and fall time equations provide the basic for high-speed CMOS design

$$C_{out} = C_{FET} + C_L \quad (7.67)$$

$$\Rightarrow t_r \approx 2.2R_p(C_{FET} + C_L) \quad (7.68)$$

$$\Rightarrow t_f \approx 2.2R_n(C_{FET} + C_L)$$

$$\Rightarrow t_r = t_{r0} + \alpha_p C_L \quad (7.69)$$

$$\Rightarrow t_f = t_{f0} + \alpha_n C_L$$

Case I: When  $C_L = 0$ ,

$$t_r = t_{r0} \approx 2.2R_p C_{FET} \quad (7.70)$$

$$t_f = t_{f0} \approx 2.2R_n C_{FET}$$

Case II: When  $C_L \neq 0$ ,

$$\alpha_p = 2.2R_p = \frac{2.2}{\beta_p(V_{DD} - |V_{Tp}|)} \quad (7.71)$$

$$\alpha_n = 2.2R_n = \frac{2.2}{\beta_n(V_{DD} - V_{Tn})} \quad (7.72)$$

$$\beta_p = \kappa_p' \left( \frac{W}{L} \right)_p$$

$$\beta_n = \kappa_n' \left( \frac{W}{L} \right)_n \quad (7.73)$$

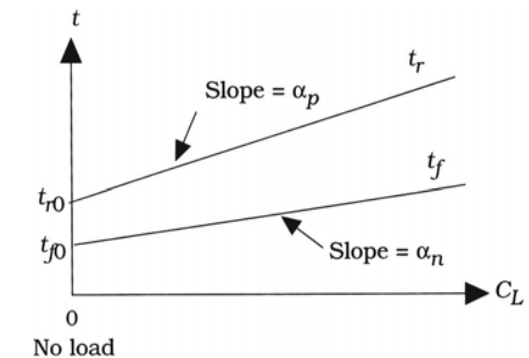
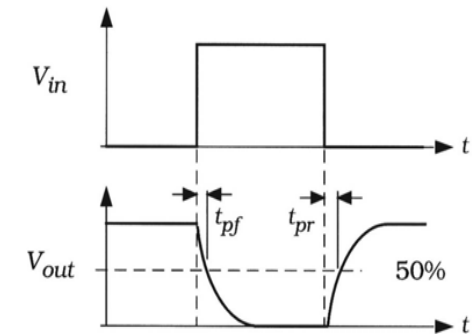
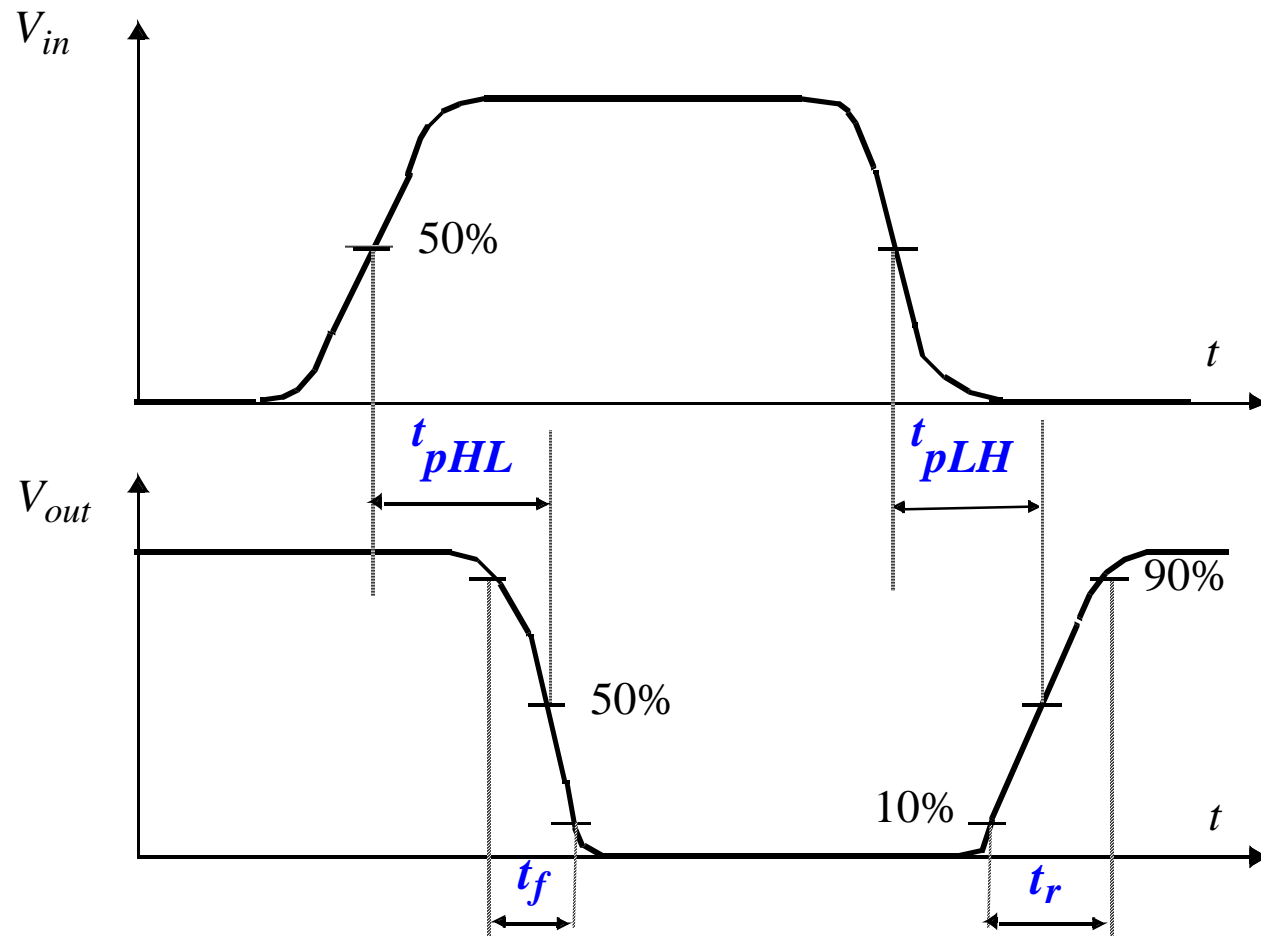


Figure 7.15 General behavior of the rise and fall time



# Delay Definitions



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# Power Dissipation (1/2)

- The current  $I_{DD}$  flowing from the power supply to ground gives a dissipated power of

$$P = V_{DD} I_{DD} \quad (7.85)$$

- » Since  $V_{DD}$  is assumed to be a constant

$$P = P_{DC} + P_{dyn} \quad (7.86)$$

Where  $P_{DC}$  is the DC term and  $P_{dyn}$  is due to dynamic switching events

- » DC contribution

$$P_{DC} = V_{DD} I_{DDQ} \quad (7.87)$$

Where  $I_{DDQ}$  is leakage current

- Leakage current is very small, therefore, the value of  $P_{DC}$  is thus quite small

- » However, leakage power on today is critical for low-power Design

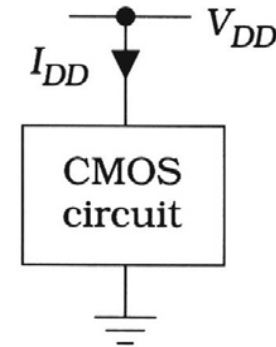
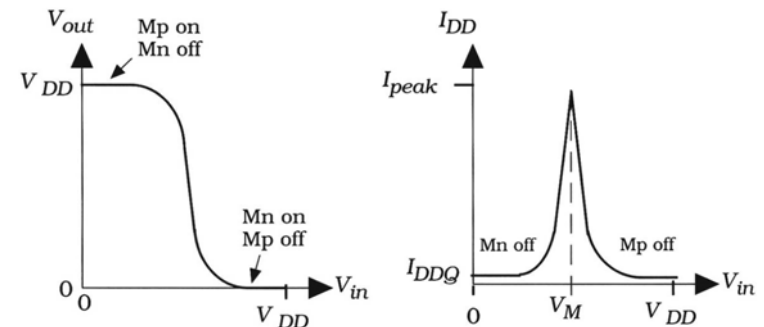


Figure 7.16 Origin of power dissipation calculation



(a) VTC

(b) DC current

Figure 7.17 DC current flow

# Power Dissipation (2/2)

□ Dynamic power dissipation  $P_{dyn}$

$$f = \frac{1}{T} \quad (7.88)$$

- »  $P_{dyn}$  arises from the observation that a complete cycle effectively creates a path for current to flow from the power supply to ground

$$Q_e = C_{out} V_{DD} \quad (7.89)$$

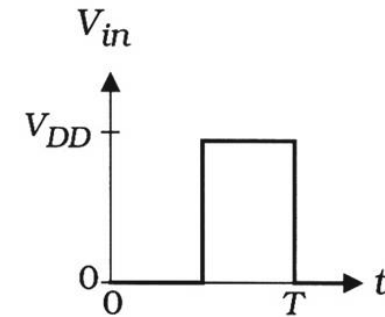
- » The average power dissipation over a single cycle with a period  $T$  is

$$P_{av} = V_{DD} I_{DD} = V_{DD} \left( \frac{Q_e}{T} \right) \quad (7.90)$$

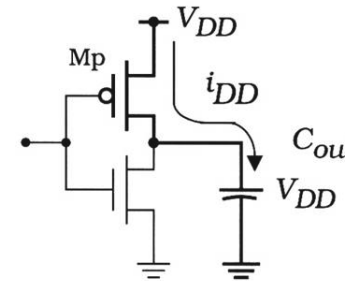
$$\Rightarrow P_{sw} = C_{out} V_{DD}^2 f \quad (7.91)$$

$$P = \underbrace{V_{DD} I_{DDQ}}_{\text{DC term}} + \underbrace{C_{out} V_{DD}^2 f}_{\text{dynamic power term}} \quad (7.92)$$

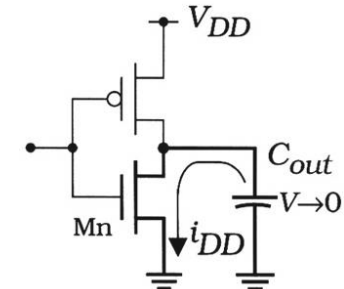
DC term    dynamic power  
term



(a) Input voltage



(b) Charge



(c) Discharge

Figure 7.18 Circuit for finding the transient power dissipation

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# NAND Analysis (1/2)

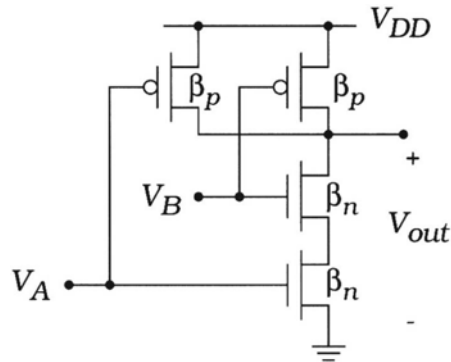


Figure 7.19 NAND2 logic circuit

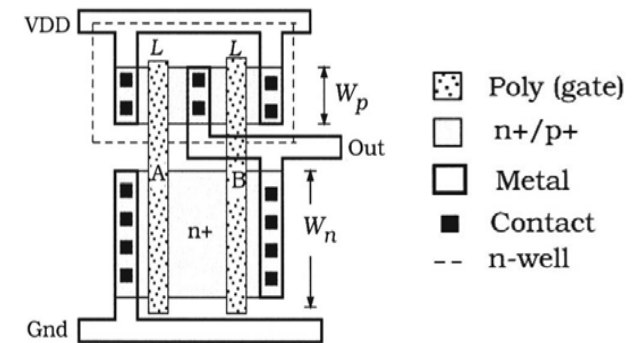
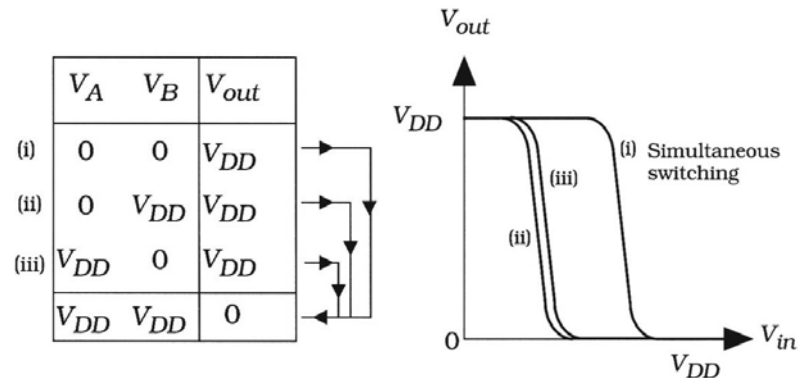


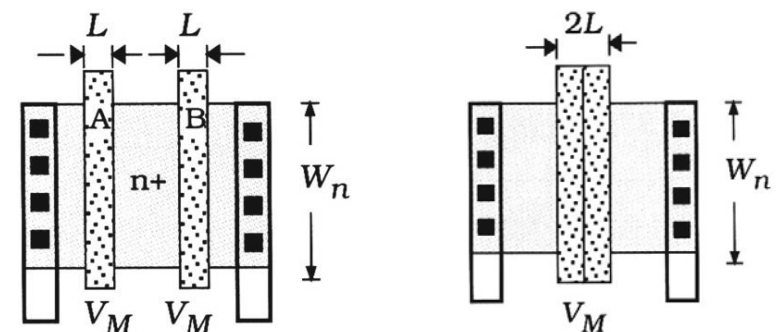
Figure 7.21 Layout of NAND2 for  $V_M$  calculation



(a) Transition table

(b) VTC family

Figure 7.20 NAND 2 VTC analysis



(a) Separate transistors

(b) Single equivalent FET

Figure 7.22 Simplification of the series-connected nFETs

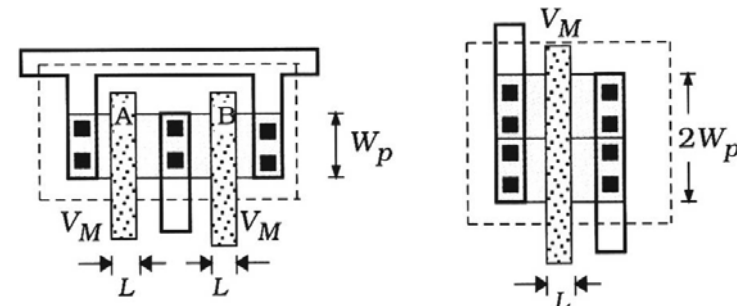
# NAND Analysis (2/2)

- Find  $V_M$  for the case of simultaneous switching, where the nFET and pFET transconductance are  $(\beta_n/2)$  and  $2\beta_p$

$$\frac{(\beta_n/2)}{2}(V_M - V_{Tn})^2 = \frac{(2\beta_p)}{2}(V_{DD} - V_M - |V_{Tp}|)^2 \quad (7.93)$$

$$V_M = \frac{V_{DD} - |V_{Tp}| + \frac{1}{2}\sqrt{\frac{\beta_n}{\beta_p}}V_{Tn}}{1 + \frac{1}{2}\sqrt{\frac{\beta_n}{\beta_p}}} \quad (7.94)$$

$$V_M = \frac{V_{DD} - |V_{Tp}| + \frac{1}{N}\sqrt{\frac{\beta_n}{\beta_p}}V_{Tn}}{1 + \frac{1}{N}\sqrt{\frac{\beta_n}{\beta_p}}} \quad (7.95)$$



(a) Separate transistors (b) Single equivalent FET

Figure 7.23 Simplification of the series-connected nFETs

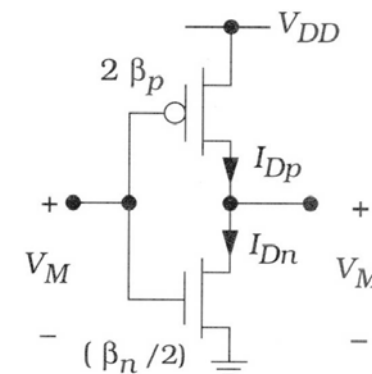


Figure 7.24 Simplified VM circuit for the NAND2 gate

# NOR Analysis

$$\frac{(2\beta_n)}{2}(V_M - V_{Tn})^2 = \frac{(\beta_p/2)}{2}(V_{DD} - V_M - |V_{Tp}|)^2 \quad (7.96)$$

$$V_M = \frac{V_{DD} - |V_{Tp}| + 2\sqrt{\frac{\beta_n}{\beta_p}}V_{Tn}}{1 + 2\sqrt{\frac{\beta_n}{\beta_p}}} \quad (7.97)$$

$$V_M = \frac{V_{DD} - |V_{Tp}| + N\sqrt{\frac{\beta_n}{\beta_p}}V_{Tn}}{1 + N\sqrt{\frac{\beta_n}{\beta_p}}} \quad (7.98)$$

$$P_{DC} = V_{DD}I_{DDQ} \quad (7.99)$$

$$P_{sw} = C_{out}V_{DD}^2 f_{gate} \quad (7.100)$$

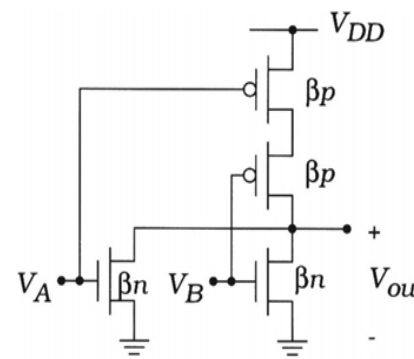


Figure 7.25 NOR2 circuit

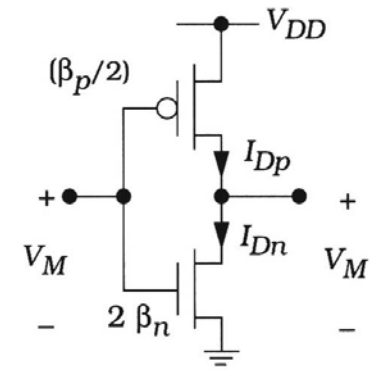
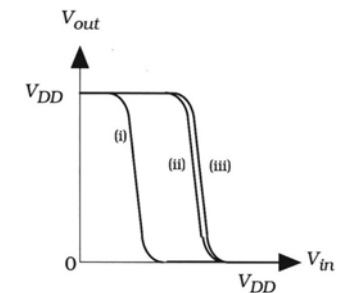


Figure 7.27 NOR23 VM calculation

	$V_A$	$V_B$	$V_{out}$	
	0	0	$V_{DD}$	
(iii)	0	$V_{DD}$	0	
(ii)	$V_{DD}$	0	0	
(i)	$V_{DD}$	$V_{DD}$	0	

(a) Transition table



(b) VTC family

Figure 7.26 NOR 2 VTC analysis



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# NAND Switching Times (1/2)

□ Figure 7.28

$$C_{out} = C_{FET} + C_L \quad (7.101)$$

$$C_{FET} = C_{Dn} + 2C_{Dp} \quad (7.102)$$

$$R_p = \frac{1}{\beta_p (V_{DD} - |V_{Tp}|)}, \quad R_n = \frac{1}{\beta_n (V_{DD} - V_{Tn})} \quad (7.103)$$

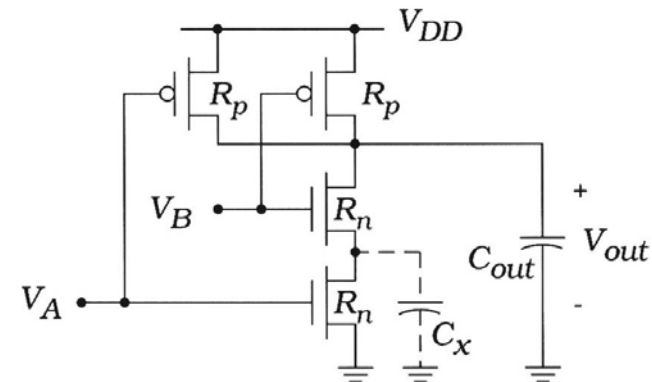


Figure 7.28 NAND2 circuit for transient calculations

□ Figure 7.29 (a)

$$V_{out}(t) = V_{DD} [1 - e^{-t/\tau_p}] \quad (7.104)$$

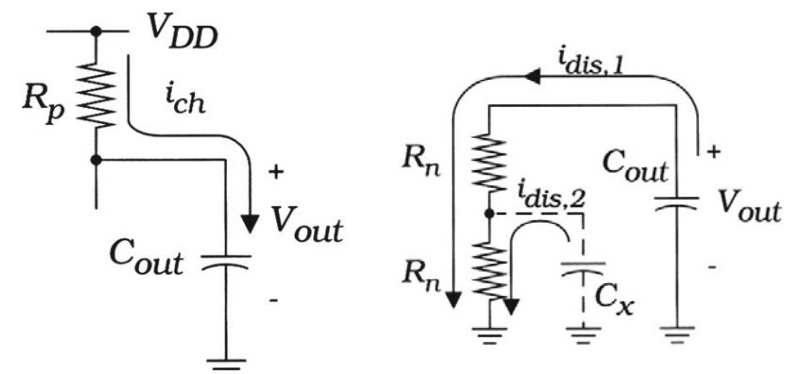
$$\text{where } \tau_p = R_p C_{out} \quad (7.105)$$

$$t_r \approx 2.2\tau_p \quad (7.106)$$

$$t_r = t_0 + \alpha_0 C_L \quad (7.107)$$

$$t_0 = 2.2R_p C_{FET} \quad (7.108)$$

$$\alpha_0 = 2.2R_p \quad (7.109)$$



(a) Charge circuit

(b) Discharge circuit

Figure 7.29 NAND2 subcircuits for estimating rise and fall times

# NAND Switching Times (2/2)

$$V_{out}(t) = V_{DD} e^{-t/\tau_n} \quad (7.110)$$

$$\tau_n = R_n (2C_{out} + C_X) \quad (7.120 \text{ from } 7.111)$$

$$\tau_n = C_{out} (R_n + R_n) + C_X R_n \quad (7.111)$$

$$C_{eff} = 2C_{out} + C_X \quad (7.121)$$

$$\tau_n = \tau_{n1} + \tau_{n2} \quad (7.112)$$

$$\tau_n = C_{out} (2R_n) + C_X R_n \quad (7.122)$$

$$\text{where } \tau_{n1} = C_{out} (R_n + R_n) \quad (7.113)$$

$$\tau_{n2} = C_X R_n \quad (7.114)$$

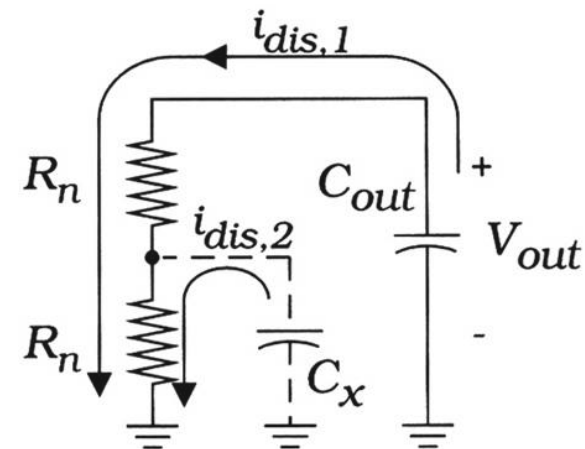
$$t_f \approx 2.2\tau_n \quad (7.115)$$

$$t_f \approx 2.2[(C_{FET} + C_L)(2R_n) + C_X R_n] \quad (7.116)$$

$$t_f = t_1 + \alpha_1 C_L \quad (7.117)$$

$$t_1 = 2.2R_n (2C_{FET} + C_X) \quad (7.118)$$

$$\alpha_1 = 4.4R_n \quad (7.119)$$



(b) Discharge circuit

# NOR Switching Times (1/2)

□ Figure 7.30

$$C_{out} = C_{FET} + C_L \quad (7.123)$$

$$C_{FET} = 2C_{Dn} + C_{Dp} \quad (7.124)$$

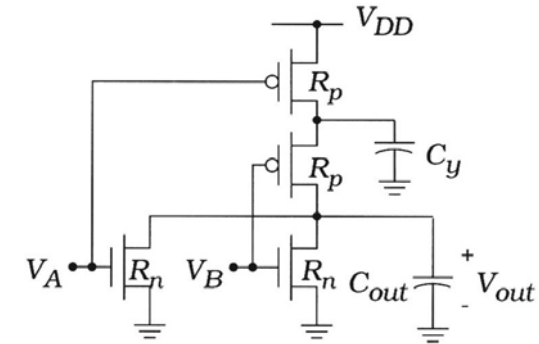


Figure 7.30 NOR2 circuit for switch time calculations

□ Figure 7.31 (a)

$$V_{out}(t) = V_{DD} e^{-t/\tau_n} \quad (7.125)$$

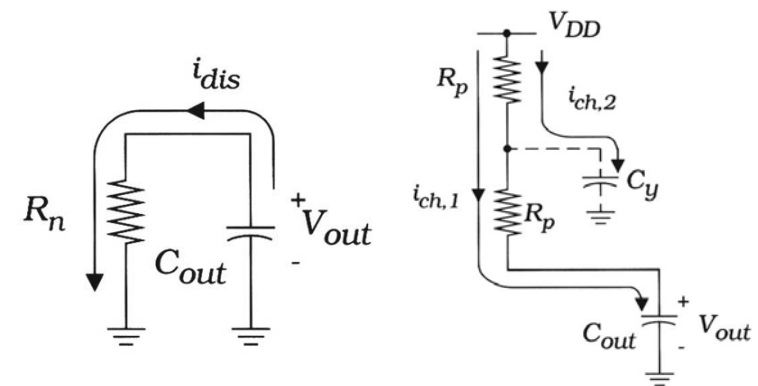
$$\tau_n = R_n C_{out} \quad (7.126)$$

$$t_f \approx 2.2\tau_n \quad (7.127)$$

$$t_f = t_1 + \alpha_1 C_L \quad (7.128)$$

$$t_1 = 2.2R_n C_{FET} \quad (7.129)$$

$$\alpha_1 = 2.2R_n \quad (7.130)$$



(a) Discharge circuit

(b) Charge circuit

Figure 7.31 Subcircuits for the NOR2 transient calculations

# NOR Switching Times (2/2)

□ Figure 7.31 (b)

$$V_{out}(t) = V_{DD}[1 - e^{-t/\tau_p}] \quad (7.131)$$

$$\tau_1 = C_{out}(R_p + R_p) \quad (7.132)$$

$$\tau_2 = C_y R_p \quad (7.133)$$

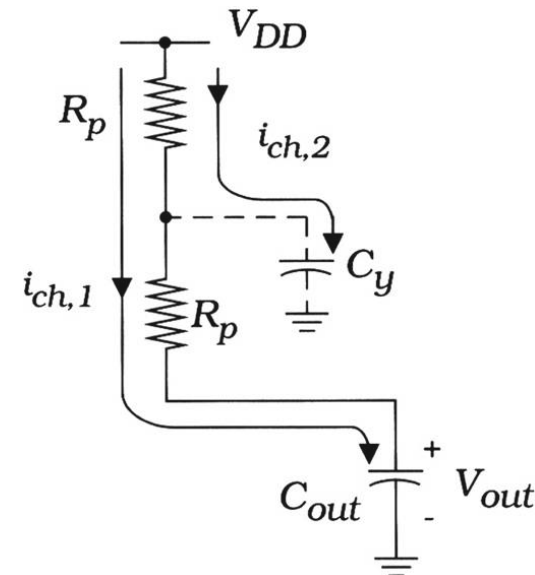
$$\begin{aligned} \tau_p &= \tau_1 + \tau_2 \\ &= C_{out}(2R_p) + C_y R_p \end{aligned} \quad (7.134)$$

$$t_r = 2.2\tau_p \quad (7.135)$$

$$t_r = t_0 + \alpha_0 C_L \quad (7.136)$$

$$\text{where } t_0 = 2.2R_p(2C_{FET} + C_y) \quad (7.137)$$

$$\alpha_0 = 4.4R_p \quad (7.138)$$



(b) Charge circuit

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# Analysis of Complex Logic Gates

$$f = \overline{x \cdot (y + z)} \quad (7.141)$$

$$\left(\frac{W}{L}\right)_{nx} = \left(\frac{W}{L}\right)_{ny} = \left(\frac{W}{L}\right)_{nz} \quad (7.142)$$

$$C_{out} = C_{FET} + C_L \quad (7.143)$$

$$\tau_n = R_n C_n + 2R_n C_{out} \quad (7.144)$$

$$\begin{aligned} t_f &= 2.2\tau_n \\ &= 2.2R_n [C_n + 2(C_{FET} + C_L)] \\ &= t_1 + \alpha_1 C_L \end{aligned} \quad (7.145)$$

$$\text{where } t_1 = 2.2R_n (C_n + 2C_{FET}) \quad (7.146)$$

$$\alpha_1 = 2.2R_n \quad (7.147)$$

$$\left(\frac{W}{L}\right)_{px} = \left(\frac{W}{L}\right)_{py} = \left(\frac{W}{L}\right)_{pz} \quad (7.148)$$

$$\tau_p = R_p C_p + 2R_p C_{out} \quad (7.149)$$

$$t_r = t_0 + \alpha_0 C_L \quad (7.150)$$

$$t_0 = 2.2R_p (C_p + 2C_{FET}) \quad (7.151)$$

$$\alpha_0 = 2.2R_p \quad (7.152)$$

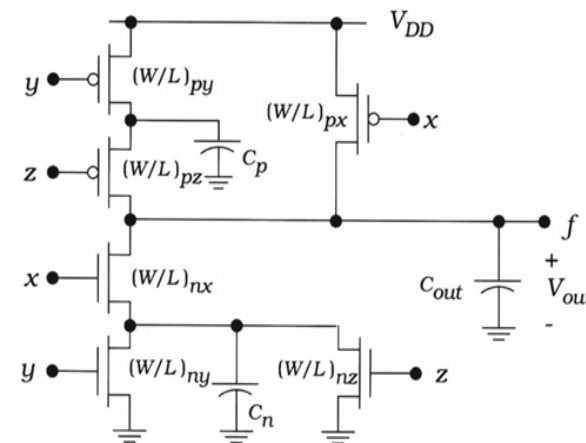


Figure 7.32 Complex logic gate circuit

# Power Dissipation

- Power dissipation in a simple inverter

$$P = V_{DD} I_{DDQ} + C_{out} V_{DD}^2 f \quad (7.153)$$

- We introduce the *activity coefficient*  $a$  that represents the probability that an output  $0 \rightarrow 1$  transition takes place during one period

A	B	$\overline{A + B}$	$\overline{A \cdot B}$
0	0	1	1
0	1	0	1
1	0	0	1
1	1	0	0

Figure 7.33 Truth tables for determining activity coefficients

$$P_{dyn} = a C_{out} V_{DD}^2 f \quad (7.154) \quad a_{NAND2} = \left(\frac{3}{4}\right)\left(\frac{1}{4}\right) = \frac{3}{16} \quad (7.158)$$

$$P_{dyn} = \sum_{i=1}^N a_i C_i V_i V_{DD} f \quad (7.155) \quad a_{NOR3} = \frac{7}{64} = a_{NAND3} \quad (7.159)$$

$$a = p_0 p_1 \quad (7.156) \quad a_{XNOR2} = \frac{1}{4} = a_{XOR2} \quad (7.160)$$

$$a_{NOR2} = \left(\frac{3}{4}\right)\left(\frac{1}{4}\right) = \frac{3}{16} \quad (7.157)$$



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# Gate Design for Transient Performance (1/2)

$$\beta = k' \left( \frac{W}{L} \right) \quad (\text{Inverter reference starting}) \quad \frac{1}{\beta_n (V_{DD} - V_{Tn})} = \frac{2}{\beta_N (V_{DD} - V_{Tn})}$$

$$R_p = \frac{1}{\beta_p (V_{DD} - |V_{Tp}|)}, \quad R_n = \frac{1}{\beta_n (V_{DD} - V_{Tn})} \quad \beta_N = 2\beta_n$$

$$\beta_n = \beta_p \quad \left( \frac{W}{L} \right)_N = 2 \left( \frac{W}{L} \right)_n$$

$$\left( \frac{W}{L} \right)_p = r \left( \frac{W}{L} \right)_n$$

$$\text{where } r = \frac{k'_n}{k'_p}$$

$$\beta_P = \beta_p \quad (\text{NAND2 vs Inverter})$$

$$R = R_N + R_N$$

$$\text{where } R_N = \frac{1}{\beta_N (V_{DD} - V_{Tn})}$$

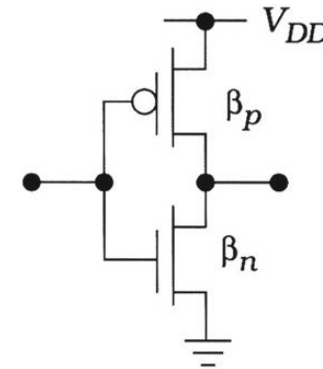
$$R = R_n = 2R_N$$

$$\beta_N = \beta_n \quad (\text{NOR2 vs Inverter})$$

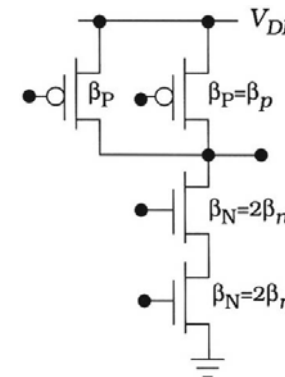
$$\frac{1}{\beta_p (V_{DD} - |V_{Tp}|)} = \frac{2}{\beta_P (V_{DD} - |V_{Tp}|)}$$

$$\beta_P = 2\beta_p$$

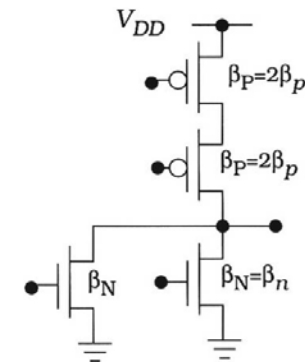
$$\left( \frac{W}{L} \right)_p = 2 \left( \frac{W}{L} \right)_P$$



(a) Inverter



(b) NAND2



(c) NOR2

Figure 7.34 Relative FET sizing

# Gate Design for Transient Performance (2/2)

- Extend to large chains as Figure 7.35

$$\beta_N = 3\beta_n, \beta_P = \beta_p \quad (7.177)$$

$$\left(\frac{W}{L}\right)_N = 3\left(\frac{W}{L}\right)_n, \left(\frac{W}{L}\right)_P = \left(\frac{W}{L}\right)_p \quad (7.178)$$

$$\beta_N = \beta_n, \beta_P = 3\beta_p \quad (7.179)$$

$$\left(\frac{W}{L}\right)_N = \left(\frac{W}{L}\right)_n, \left(\frac{W}{L}\right)_P = 3\left(\frac{W}{L}\right)_p \quad (7.180)$$

- Figure 7.36

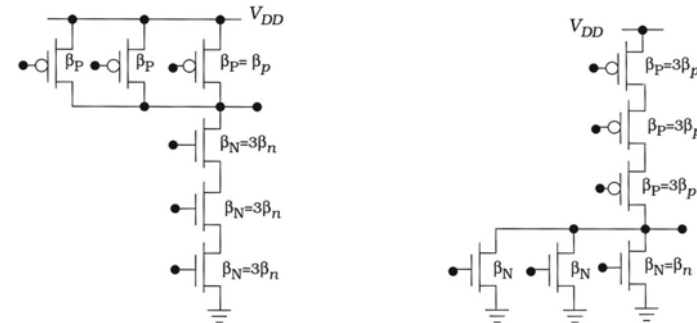
$$f = \overline{(a \cdot b + c \cdot d)} \cdot x \quad (7.181)$$

$$\beta_N = 3\beta_n = \beta_{N1} \quad (7.182)$$

$$\beta_P = 2\beta_p \quad (7.183)$$

$$\beta_{P1} = \beta_p \quad (7.184)$$

$$\beta_{P1} = \beta_P = 2\beta_p \quad (7.185)$$



(a) NAND3

(b) NOR3

Figure 7.35 Sizing for 3-input gates

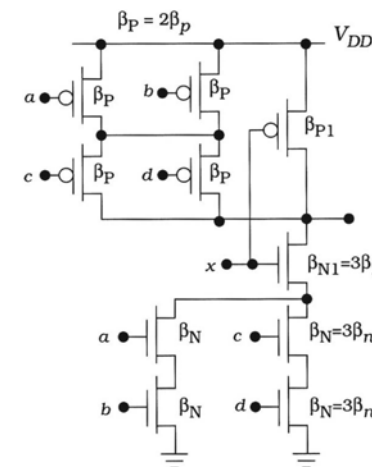


Figure 7.36 Sizing of a complex logic gate

# Outline

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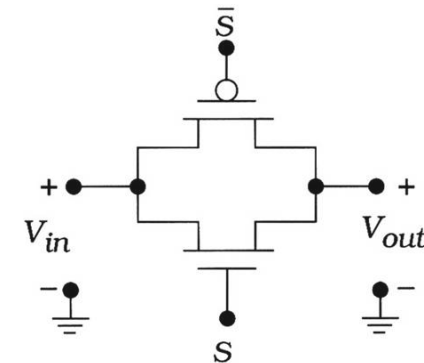
- ❑ DC Characteristic of the CMOS Inverter
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# Transmission Gates

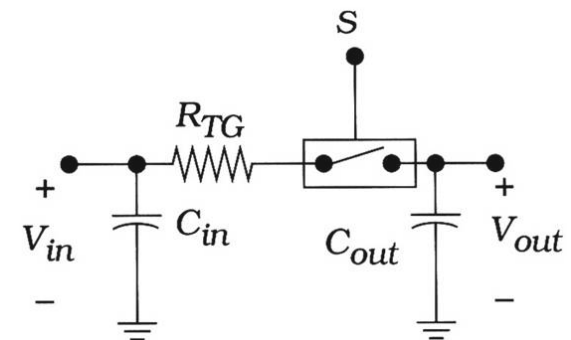
$$R_{TG} = \max(R_n, R_p) \quad (7.186)$$

$$C_{in} = C_{S,n} + C_{D,p} \quad (7.187)$$

- Large ratio of  $(W/L)$  decrease the resistance, but a large  $W$  implies large capacitances



(a) Circuit



(b) RC model

Figure 7.37 Transmission gate modeling

# Pass Transistor

- ❑ Pass FETs can be used in place of transmission gates in most circuits
  - » Less area and wiring, but cannot pass the entire voltage range

$$V_{out}(t) = V_{max} \left( \frac{t/2\tau_n}{1 + t/2\tau_n} \right) \quad (7.188)$$

$$\text{where } V_{max} = V_{DD} - V_{Tn} \quad (7.189)$$

$$\lim_{t \rightarrow \infty} V_{out}(t) = V_{max} \quad (7.190)$$

$$\tau_n = R_n C_{out} \quad (7.191)$$

$$t_r = 18\tau_n \quad (7.192)$$

$$V_{out}(t) = V_{max} \left( \frac{2e^{-(t/\tau_n)}}{1 + e^{-(t/\tau_n)}} \right) \quad (7.193)$$

$$\lim_{t \rightarrow \infty} V_{out}(t) = 0 \quad (7.194)$$

$$t_f = \ln(19)\tau_n \approx 2.94\tau_n \quad (7.195)$$

$$t_r \approx 6t_f \quad (7.196)$$

$$t_r = 2.94\tau_p \quad (7.197)$$

$$\text{where } \tau_p = R_p C_{out} \quad (7.198)$$

$$V_{min} = |V_{Tp}| \quad (7.199)$$

$$t_f = 18\tau_p \quad (7.200)$$

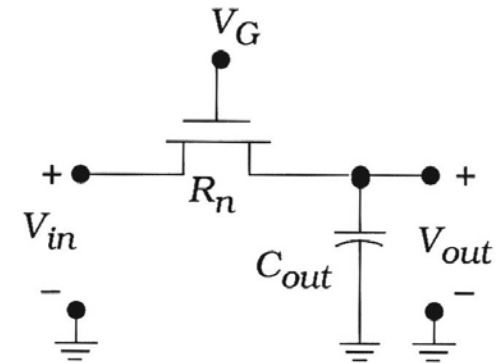


Figure 7.38 nFET pass transistor

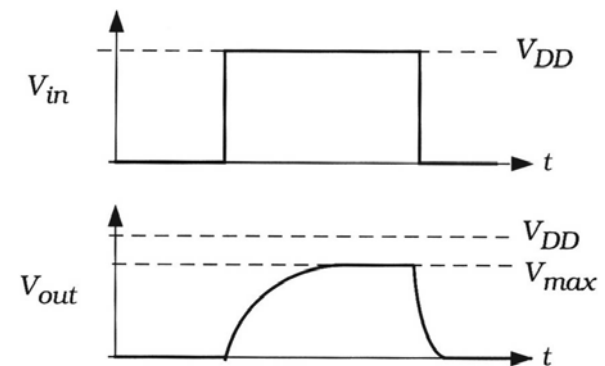


Figure 7.39 Voltage waveforms for a nFET pass transistor